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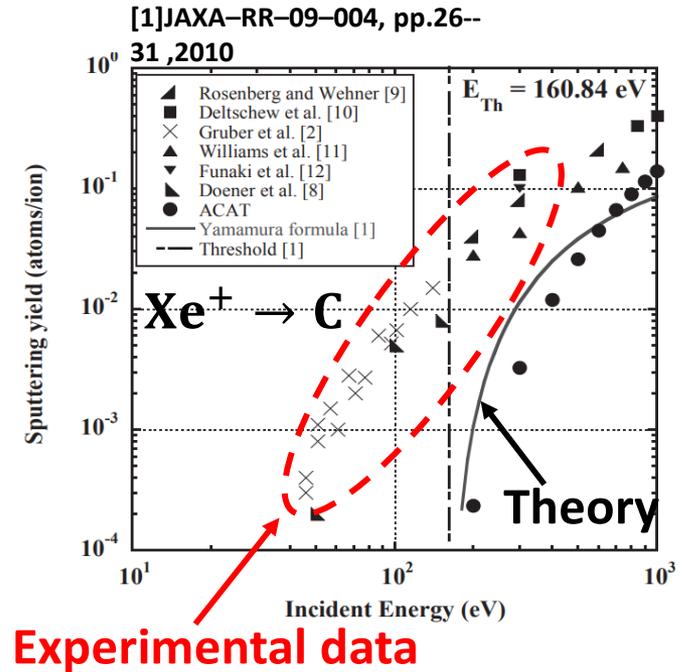
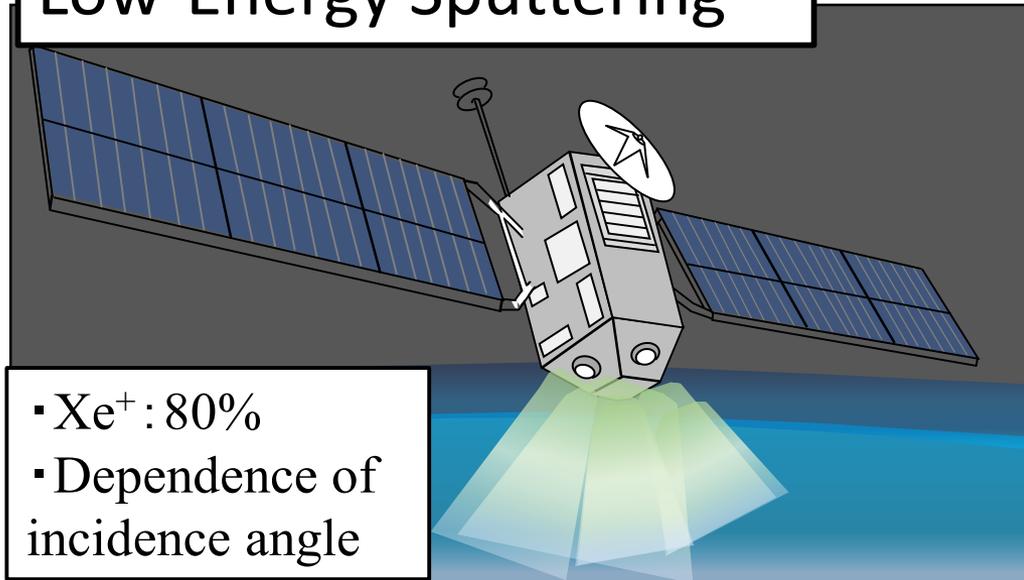
Beam Profile Measurements of Decelerated Multicharged Xe Ions from ECRIS for Estimating Low Energy Damage on Satellites Components

Koichi Sato, Kazuki Okumura, Shuhei Harisaki,
Wataru Kubo, Issei Owada, Kazuki Tsuda, and Yushi Kato

*Division of Electrical, Electronic and Inforcommunications Engineering,
Graduate School of Engineering, Osaka University*

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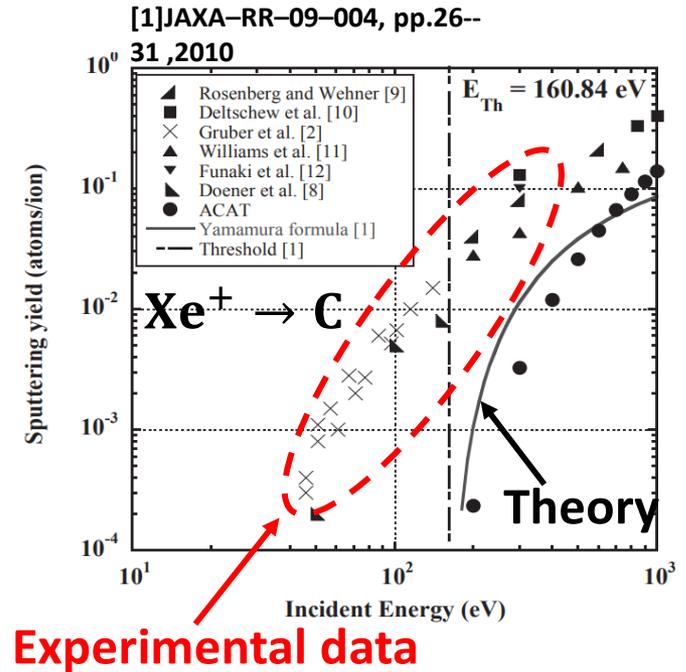
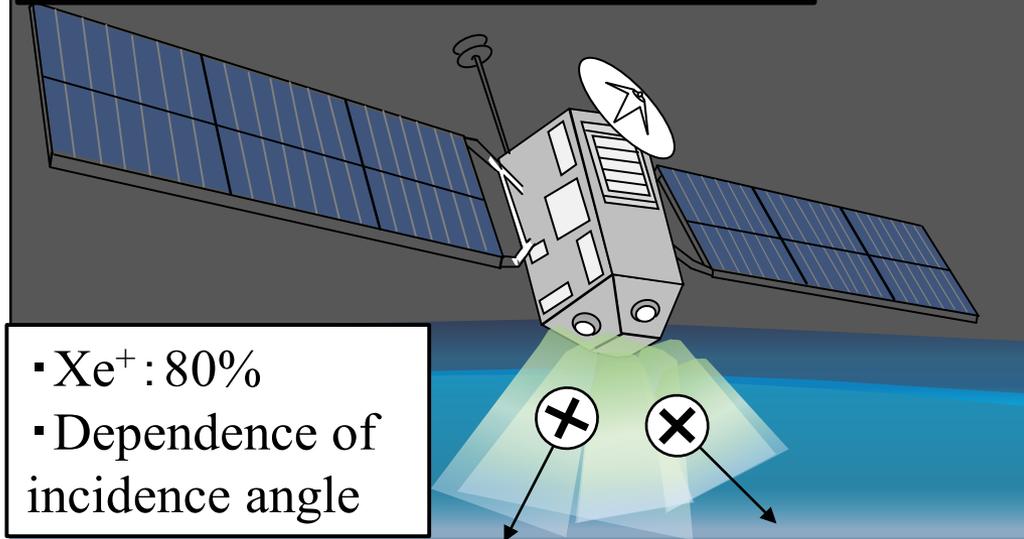
Low-Energy Sputtering



- ➡ In designing satellites for 10–15 years of operation, low energy sputtering cannot be ignored.
- ➡ Low energy sputtering yield has some different results in experimental data and theory.

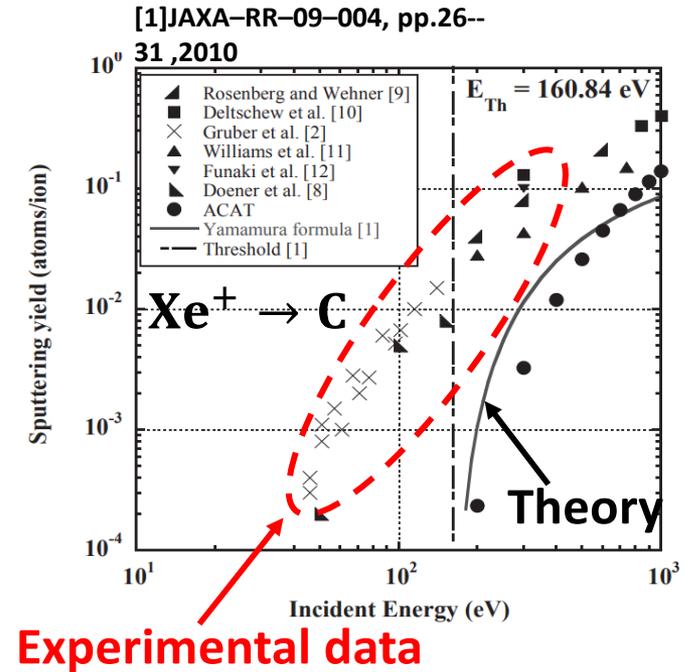
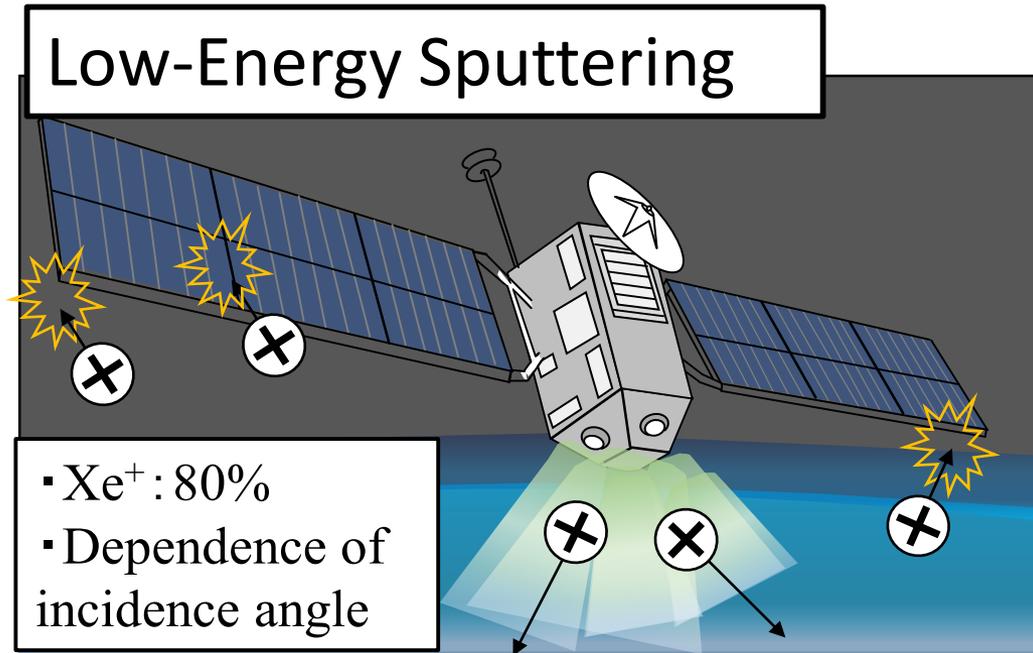
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~ In our laboratory ~

Our goal is measurement of sputtering yield by irradiating satellite components with low energy Xe ion beam.

Beam Deceleration

The amount of beam currents is not enough for irradiation when the extraction voltage is 1kV and Xe is extracted.



We extract the ion beams from high voltage 10 kV and transported into the ion beam irradiation system (IBIS) where we constructed.
And we decelerate and irradiate ion beams to the materials.

Previous studies

- Experimental setup using an existing ECRIS for decelerated ion beams
- Improvement of beam line to increase current

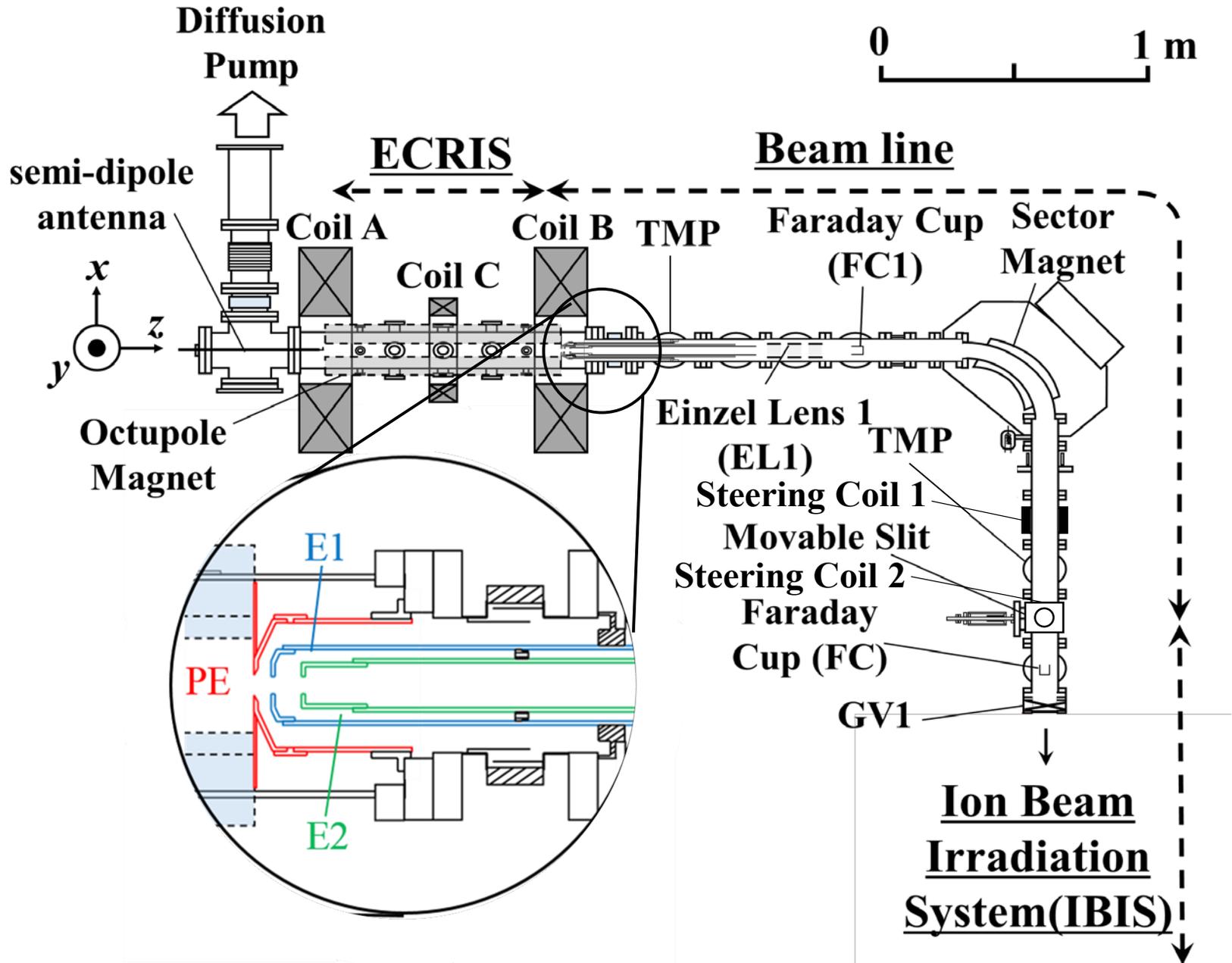
Construction of equipment for irradiation

- Problem: Uniformity of beam profile on the sample about 1cm^2
⇒ We measure the two dimensional profiles of the decelerated beam
- Xe, Ar Deceleration Experiments
→ Measurements of beam current in the low energy region
- Measurements of beam profiles in the low energy region
- Calculations of the current density & Evaluating of the dose amount
→ Estimation of irradiation time

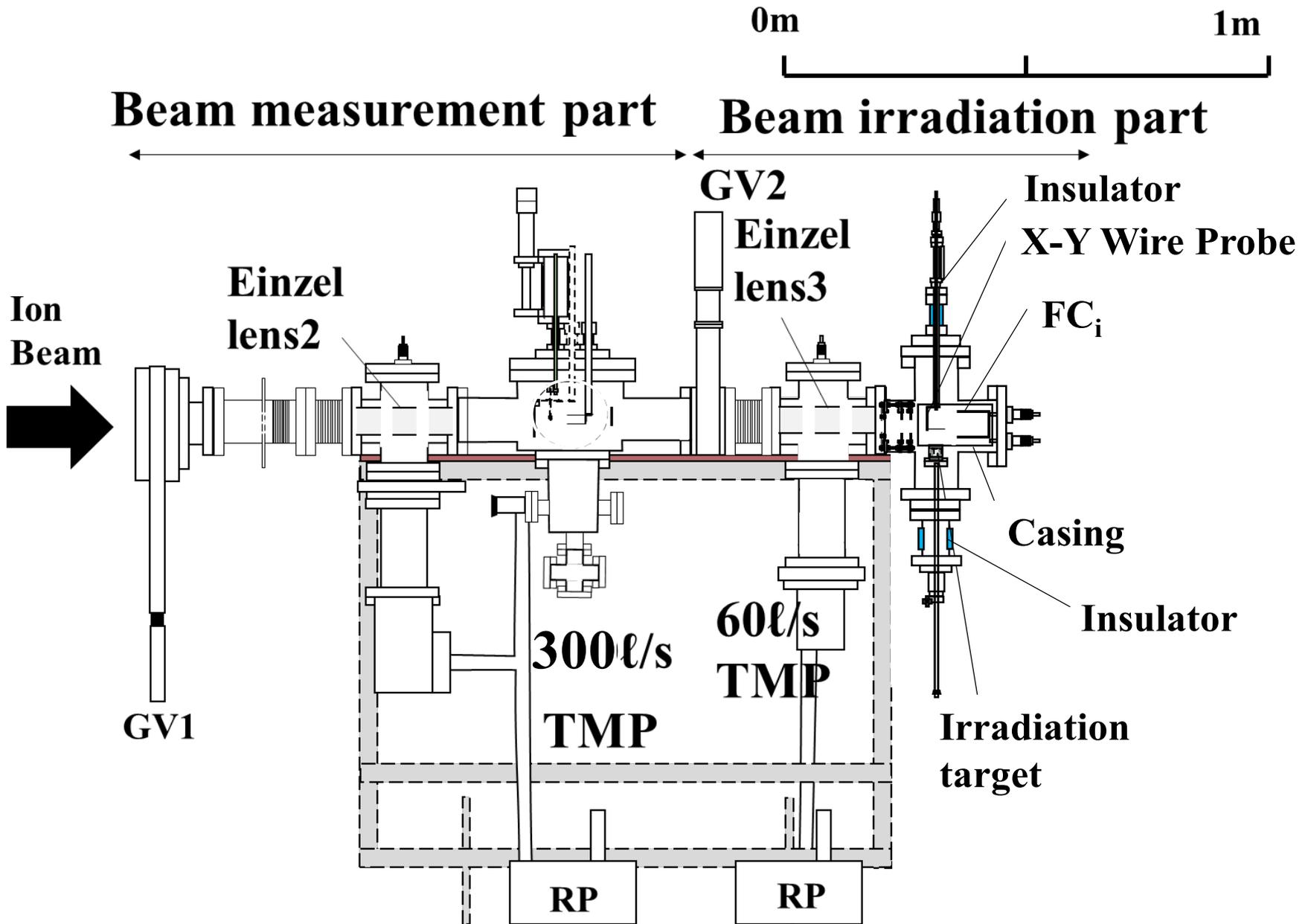
ECRIS & Beam line

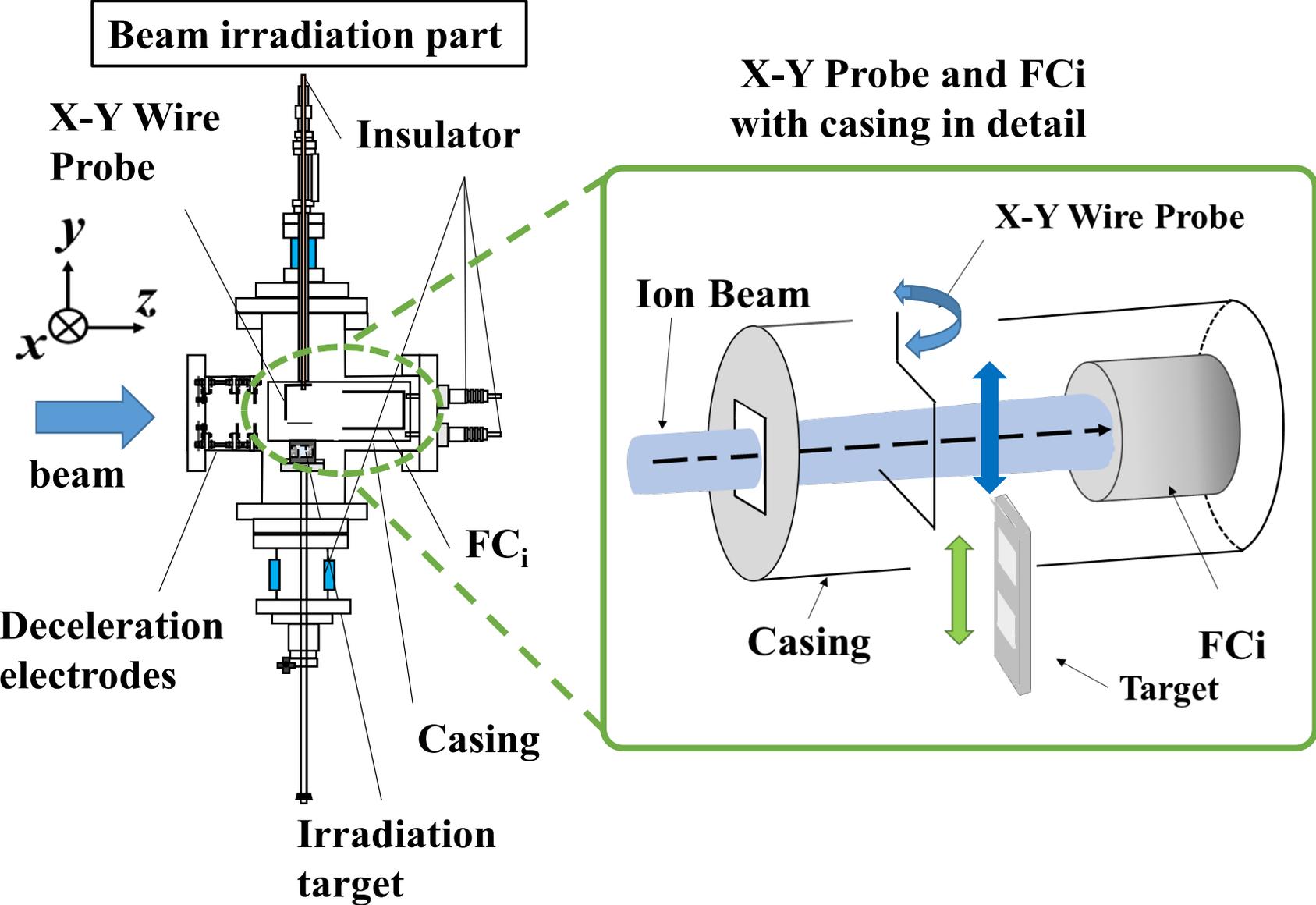


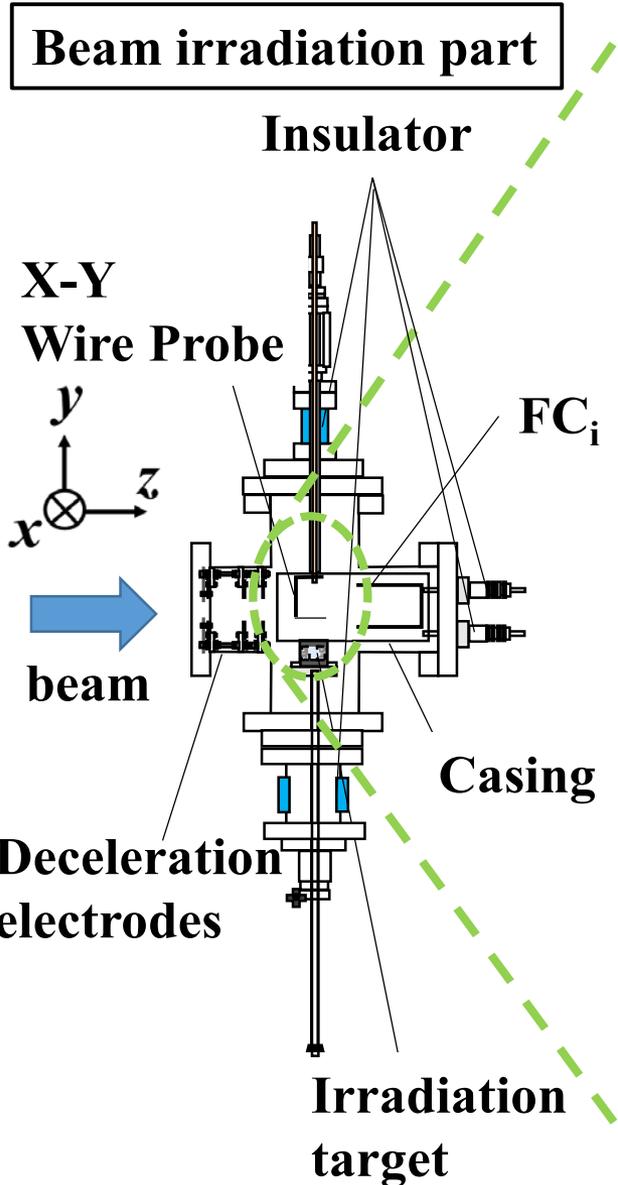
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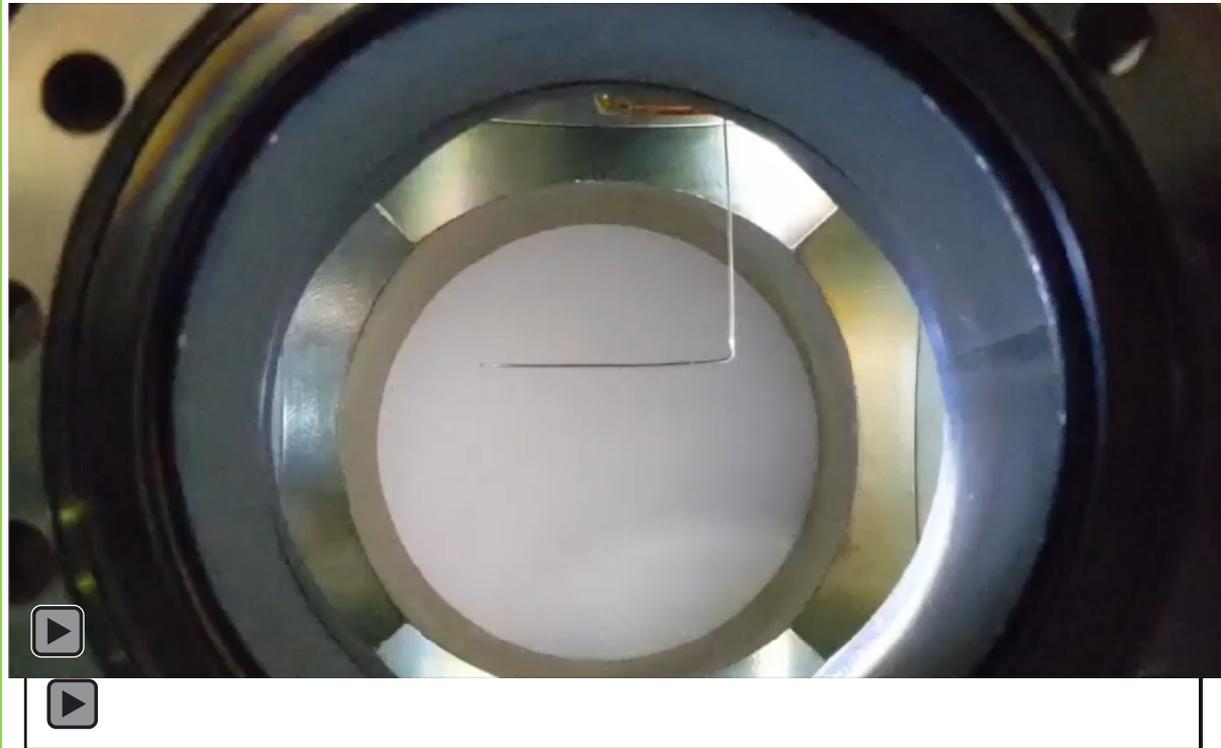
Ion Beam Irradiation System (IBIS)



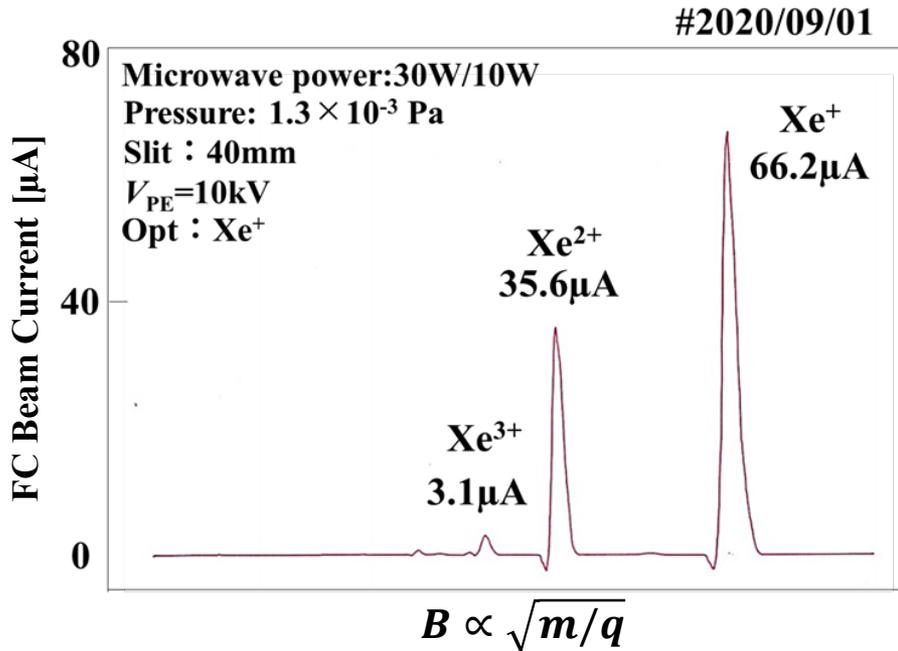




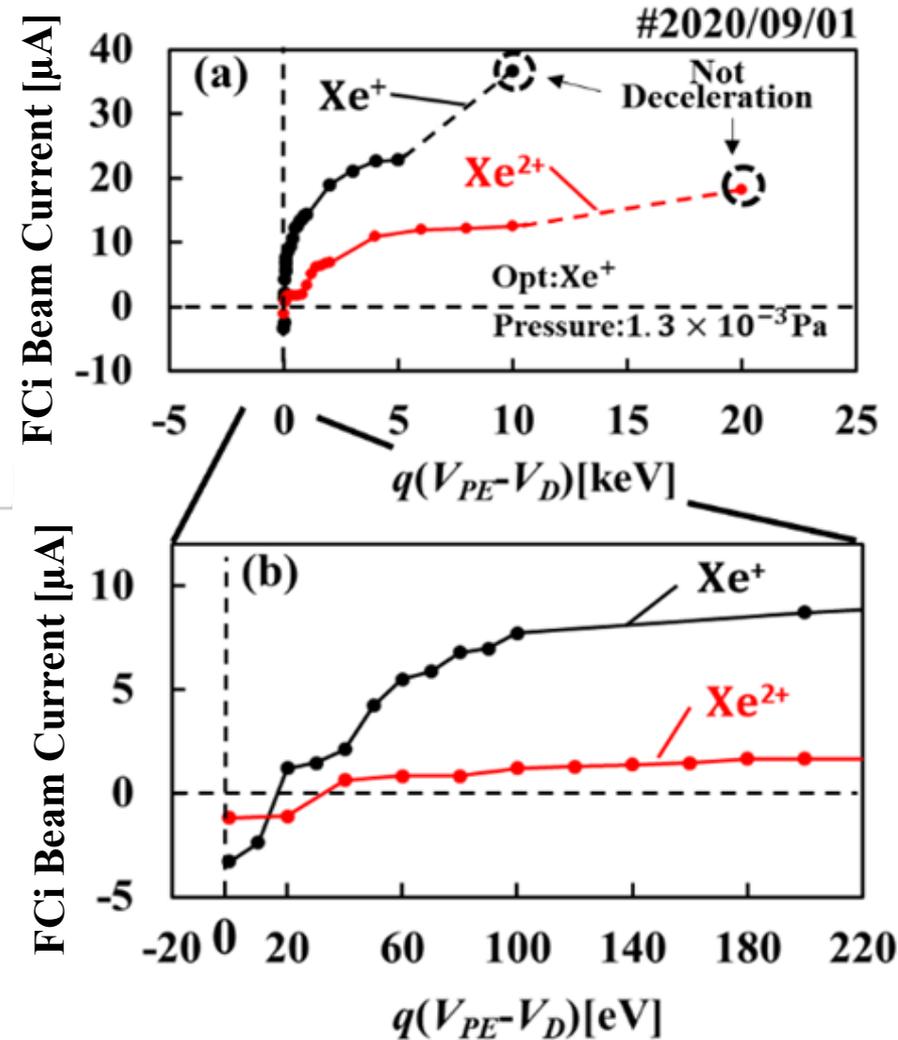
Movement of the X-Y wire probe during measurements of two dimensional profiles



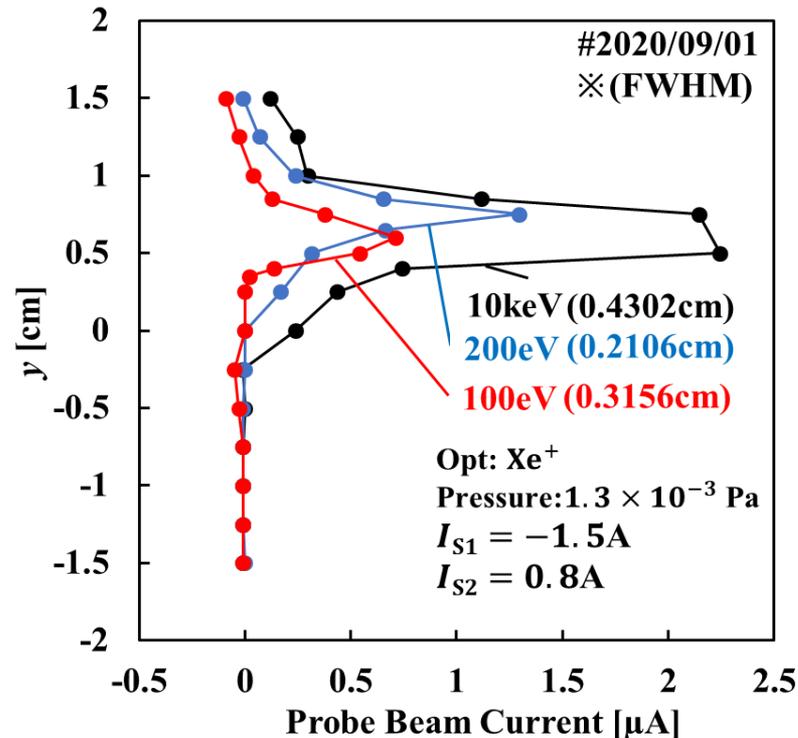
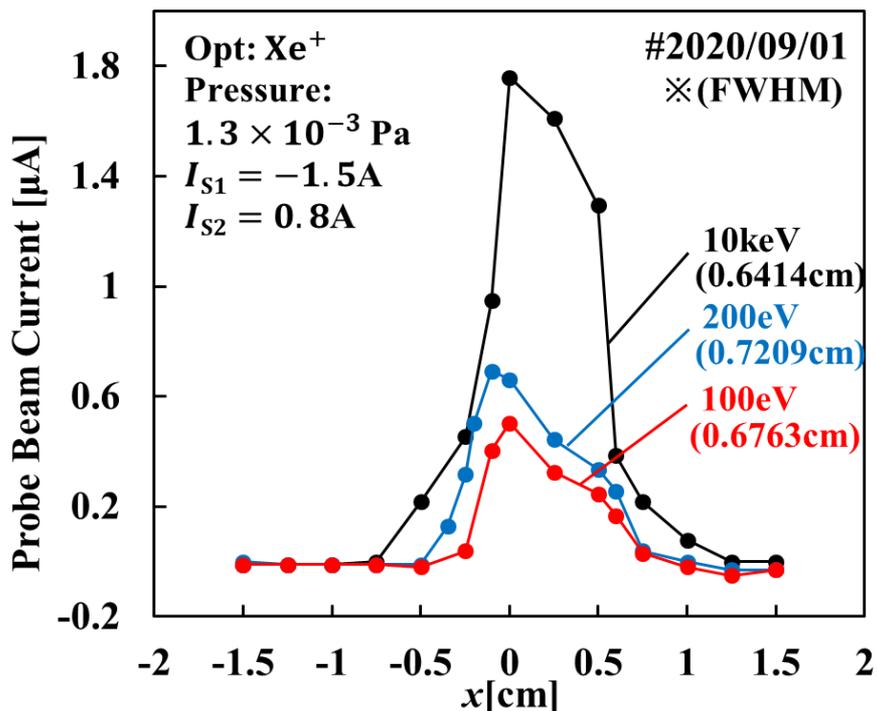
Xe Deceleration Experiment



We found that there was sufficient current to conduct irradiation experiments in the low energy region (100~200eV).



Measurements of Decelerated Xe⁺ Ion Beam Profiles



Irradiation condition of Xe ⁺ (200eV)		
	Si	SiO ₂
Irradiation Time [min]	7	3
erosion[nm]	20	20
Y[mm ³ /C]	0.012	0.033
Current Density[A/cm ²]	4.33E-04	4.33E-04

Irradiation condition of Xe ⁺ (100eV)		
	Si	SiO ₂
Irradiation Time [min]	27	5
erosion[nm]	10	10
Y[mm ³ /C]	0.002	0.011
Current Density[A/cm ²]	3.20E-04	3.20E-04

Summary

- ➡ Sufficient beam current in the low energy region (about 100eV to 500eV) for irradiation experiments
- ➡ We succeeded in acquiring the profile of decelerated beam.
- ➡ Evaluation of high precision dose amount and irradiation time

Future Plan

- ➡ Further improvement of deceleration electrode and irradiation system to shorten irradiation time
- ➡ Irradiation experiments for various materials